

Time	Session MO1: Bio/Life Sciences	Session MO2: Fundamentals	Session MO3: Geological/Cosmochemistry
Room	Churchill (350)	Rossetti (100)	Wren (100)
Morning Chair	Anna Belu	John Fletcher	Albert Fahey NIST
8:40		Welcome from Conference Chairs	
9:00	Plenary 1 Introduced by Joe Gardella in the Churchill Theatre Prof. A. Benninghoven, Univ. Munster 3KBWFT History of SIMS and the Conference		
9:20			
9:40			
10:00	Bui: <i>Development of a Methodology for the Characterization of Complex Protein Films by TOF-SIMS Imaging</i>	Prof. Zbigniew Postawa: <i>Depth Profiling by Cluster Projectiles as Seen by Computer Simulations</i>	Verovkin: <i>Analysis of Genesis Solar Wind Collectors with Laser Post-Ionization Mass Spectrometry</i>
10:20	Burns: <i>Going in the Reverse Order: Picking Biological Applications Suitable for ToF-SIMS</i>	Invited	Siljeström (student): <i>ToF-SIMS Analysis of Single Oil-bearing Fluid Inclusions in Search of Organic Biomarkers</i>
10:40	Coffee	Coffee	Coffee
11:00	Moon: <i>Surface Chemistry and Structural Changes of Collagen Fibers due to Thermal and Enzymatic Denaturation Observed by Secondary Ion Mass Spectrometry</i>	Garrison: <i>Ejection of Molecules and Fragments due to C<sub>60</sub> Bombardment</i>	Liu: <i>A New Approach to Measuring D/H Ratios with the Cameca IMS-7F</i>
11:20	Sodhi: <i>Chemical Composition and Microstructure of Waxy Plant Surfaces: Triterpenoids and Fatty Acid Derivatives on Leaves of Kalanchoe Daigremontiana</i>	Wucher: <i>Retrospective Sputter Depth Profiling using 3D Mass Spectral Imaging</i>	Dimov: <i>Speciation and Quantification of Surface Gold in Carbonaceous Matter by TOF-SIMS: A New Approach in Characterizing Losses During the Gold Recovery Process</i>
11:40	Vaidyanathan: <i>ToF-SIMS Investigations of Microalgae Using a Cluster Ion Source</i>	Weidtmann (student): <i>Influence of the Polar Angle of Incidence on Secondary Ion Generation in Self-Sputtering of Silver</i>	Hart: <i>Development of a ToF-SIMS Technology as a Predictive and Diagnostic Tool for the Need of the Mineral Processing Industry</i>
12:00	Tyler: <i>Tracking and Detection of 15N Labeled Cells with ToF-SIMS</i>	Delcorte: <i>Computer Simulation of Structural Effects in Cluster-Induced Sputtering of Organic Crystals</i>	Nguyen (student): <i>TOF-SIMS Studies of Intercalated Gibbsite</i>
12:20	Li (student): <i>Investigation of Melamine Induced Kidney Stones Using Ambient Mass Spectrometry</i>	Berghmans (student): <i>Cesium Retention During Sputtering with Low Energy Cs<sup>+</sup> Andoxygen Flooding</i>	Dr. Noriko Kita: <i>High Precision SIMS Oxygen Isotope Analyses of Geological Materials: Accuracy, Surface Topography and Crystal Orientation</i>
12:40	Audinot: <i>NanoSIMS50 Imaging of Thin Samples Coupled with Neutral Cesium</i>	Williams: <i>On the Effect of Oxygen Flooding on the Detection of Noble Gas Ions in a SIMS Instrument</i>	
13:00	Lunch Break	Lunch Break	Lunch Break
13:20	Lunch Break	Lunch Break	Lunch Break
13:40	Lunch Break	Lunch Break	Lunch Break

Session Chair	Uilli Krull	Kristin Krantzman	Bonnie Tyler
14:00	Antonino Licciardello: <i>ToF-SIMS of Molecular Materials: From Polymers to Supramolecular Systems</i>	Williams: <i>Negative Ion Yield Variations for Cs<sup>+</sup> Bombardment of Si with O<sub>2</sub> Gas Flooding</i>	Kollmer: <i>Developments of a Novel Bismuth-Manganese Emitter for G-SIMS Spectroscopy and Imaging</i>
14:20	Invited	Mody (student): <i>Computer Modelling of the Interaction of keV Cluster and MeV Monomer Ions with Molecular Solids</i>	Reichenbach: <i>Interactive Spatio-Spectral Analysis of Three-Dimensional Chemical Images from ToF-SIMS</i>
14:40	Castner: <i>ToF-SIMS Characterization of Patterned Protein Surfaces</i>	Fernandez-Lima: <i>Photon Emission from Massive Projectile Impacts on Solids</i>	Henderson: <i>Comparison of Alternative Multivariate Approaches in 2D and 3D ToF-SIMS Image Analysis</i>
15:00	Piehowski (student): <i>Sub-Micrometer Biological Imaging with ToF-SIMS: Measuring Lipid Domains at Single Cells</i>	Willingham (student): <i>Investigating the Fundamentals of Molecular Depth Profiling Using Strong-field Photoionization of Sputtered Neutrals</i>	Milillo: <i>Image Analysis Combining SEM and ToF-SIMS Images Utilizing Principles of Image Fusion</i>
15:20	Green: <i>A Comparison of SIMS and DESI Complementarities</i>	Muramoto (student): <i>On the Way to Optimal 3D Molecular Imaging with ToF-SIMS: A Comparison between C<sub>60</sub> Single Beam and Bi<sub>n</sub>/C<sub>60</sub> Dual Beam Depth Profiling</i>	Gui: <i>Numerical Approach to Resolve Mass Interference in Depth Profiling as in SiGe</i>
15:40	Coffee	Coffee	Coffee
16:00	Lanekoff (student): <i>An In Situ Fracture Device to Image Lipids in Single Cells Using ToF-SIMS</i>	Gnaser: <i>Dynamic Computer Simulations of Cs Incorporation During Low-energy (0.2 - 3 keV) Bombardment</i>	James Ohlhausen: <i>ToF-SIMS Data Analysis - Methods and Challenges</i>
16:20	Schroeder: <i>Mapping and Quantitative Analysis of Stable Isotope Tracers in SIMS Images of Biological Tissues</i>	Lu (student): <i>Fundamental Studies of Molecular Depth Profiling using Organic Delta-layers as Model Systems</i>	Invited
16:40	Heien: <i>ToF-SIMS Imaging of Neurite Growth</i>	Ninomiya: <i>Damage Evaluation of Organic Samples under Large Ar Cluster Ion Bombardment</i>	Py (student): <i>Quantification of Germanium in Si1-xGex Alloys by Negative Mode ToF-SIMS: The Interest of the Full Spectrum Method</i>
17:00	Jackson (student): <i>A Systematic Evaluation of Sample Preparation Methods for the ToF-SIMS Imaging of Prostrate Cancer Cell Nuclei</i>	Bendler (student): <i>About the Use of Neutral Cesium Deposition in the Pre-equilibrium Regime</i>	Morris: <i>Ion, Sputter and Useful Yields for Accurate Quantification of Si1-xGex (0 &lt; x &lt; 1) using Ultra Low Energy O2+ SIMS</i>
17:20	Passarelli (student): <i>Lipid Analysis of Tissue, Cell and Thin Films using SIMS and MALDI</i>	Fisher: <i>Measuring the Effects of Cluster Ion Beam Fluence on the Depth Profile Analysis of Organics</i>	Sarra-Bournet (student): <i>ToF-SIMS Multivariate Characterization of N2-H2 Atmospheric Pressure Dielectric Barrier Discharge Surface Modification of Polymers</i>
17:40	Sodhi: <i>Bismuth Cluster Ions as a Primary Ion Source in TOF-SIMS</i>	Ngo (student): <i>Analysis and Fragmentation of Organic Samples by (low-energy) Dynamic SIMS</i>	Mayerhofer: <i>Three Dimensional Analysis of Self-Structuring Organic Thin Films with TOF-SIMS</i>

Time	Session Tu 1: FIB/Instrumentation	Session 2: Cell, Bacterial, Tissue	Session Tu 3: Fundamentals/Cluster ion
Room	Wren (100)	Churchill (350)	Rossetti (100)
Session Chair	Fred Stevie	Patrick Bertrand, Louvain la Neuve	Laurent Houssiau
8:40	Plenary 2 Introduced by Leo Lau (Churchill)		
9:00	Michael Bancroft: "The Canadian Road to See the Light - a Historical Perspective of the Development of the Canadian Light Source Facility (CLS)", with a brief update on CLS by Jeffrey Cutler		
9:20			
9:40	Li (student): <i>Optimization of FIB-SIMS by Development of Yield Enhancement Strategies</i>	Alain Brunelle: <i>In situ Chemistry and Biology with Cluster TOF-SIMS Imaging</i>	Delcorte: <i>Sputtering Soft Materials with Molecular Projectiles: A Microscopic View</i>
10:00	Fisher: <i>Advances in 2D and 3D Imaging of Organics by Means of Cluster Ion Beams and FIB Sectioning</i>	Invited	Verkhoturov: <i>Statistics of Electron and Ion Emission from Single Massive Cluster Impacts</i>
10:20	Chater: <i>FIB-SIMS Analysis of an Aluminium Alloy/SiC Metal Matrix Composite</i>	Vickerman: <i>Molecular SIMS Imaging - Spatial Resolution and Molecular Sensitivity - Have we Reached the End of the Road or is there Light at the End of the Tunnel?</i>	Gutierrez (student): <i>Molecular Dynamics Study of Metal-Organic Samples Bombarded by Kiloelectronvolt Projectiles</i>
10:40	Coffee	Coffee	Coffee
11:00	Lucille Giannuzzi: <i>A Review of FIB/SIMS</i>	Szagal: <i>Approaches for Improved Site-Specific Chemical Imaging of Cells</i>	Heile: <i>Investigations of Secondary Ion Yield Enhancing Methods in Combination</i>
11:20	Invited	Kilburn: <i>Combined Analysis of Biological Materials with NanoSIMS and TEM</i>	Brenes (student): <i>Temperature Dependent Studies of a Sputtered Physisorbed Organic Film Induced by Energetic Atomic and Cluster Projectiles</i>
11:40	Schnieders: <i>TOF-SIMS Analysis of FIB Lift-Out Specimens</i>	Lee: <i>ToF-SIMS and Confocal Imaging to Assist Assessing In Vitro Cytotoxicity of Human Keratinocyte Cell Treated with ZnO Nanoparticles</i>	Prabhakaran (student): <i>Secondary Ion Yield Enhancement in Organic Samples due to the Au/Pt Nanoparticle Condensation and their Substrate Effects</i>
12:00	Chater: <i>Three-dimensional Reconstruction of a Ni-Al<sub>2</sub>O<sub>3</sub> Composite Film by FIB-SIMS</i>	Castner: <i>ToF-SIMS 2D and 3D Imaging of HeLa Cells Treated with siRNA and BrdU</i>	Krantzman: <i>Fluence Effects during Bombardment of Si with C<sub>60</sub></i>
12:20	Wirtz: <i>Storing Matter: A New Quantitative and Sensitive Analytical Technique Based on Sputtering and Collection of Sample Material</i>	Park (student): <i>ToF-SIMS Analysis of Myocardial Infarcted Tissue</i>	Webb: <i>The Effect of the C:H Ratio on the Sputtering of Molecular Solids</i>
12:40	Becker (student): <i>The Storing Matter Technique: Application to PS, PVC, and PMMA using Au Collectors</i>	Rabbani (student): <i>Exploring Sub-Cellular Imaging on the Buncher-ToF J105 3D Chemical Imager</i>	Ninomiya: <i>Analysis of Organic Semiconductor Multilayers with Ar Cluster SIMS</i>
13:00	Lunch Break	Lunch Break	Lunch Break
13:20	Lunch Break	Lunch Break	Lunch Break

13:40	Lunch Break	Lunch Break	Lunch Break
Session Chair	Birgit Hagenhoff	David Castner	Arnaud Delcorte
14:00	Plenary 3 Introduced by Rana Sodhi (Churchill)		
14:20	Michael Sefton 8YLSLX		
14:40	New New Biomaterials		
15:00	David McPhail: <i>Applications of Focused Ion Beams and Focused Ion Beam-SIMS</i>	Lau (student): <i>Study of Polymer Chain Folding by Time-of-Flight Secondary Ion Mass Spectrometry</i>	Della Negra: <i>Massive Clusters: Secondary Emission from qkeV to qMeV. New Emission Processes? New SIMS Probe?</i>
15:20	Invited	Aoyagi: <i>Evaluation of Immobilized Polypeptides with Different C-terminal Residues using Argon-Cluster Secondary Ion Mass Spectroscopy</i>	Della Negra: <i>The Pegase Project: A New Solid Surface Probe: Focussed Massive Cluster Ion Beams</i>
15:40	Coffee	Coffee	Coffee
16:00	Li (student): <i>Rectilinear Ion Trap-secondary Ion Mass Spectrometer (RIT-SIMS) for Surface Modification and In Situ Analysis</i>	Gillen: <i>Useful Yields of Organic Molecules under Cluster Bombardment</i>	Ian Gilmore: <i>Cluster Primary Ion Sputtering: Correlation of Secondary Ion Intensities in TOF SIMS</i>
16:20	Hill: <i>A New Time of Flight SIMS Instrument for 3-Dimensional Imaging and Analysis</i>	Appawu (student): <i>ToF-SIMS Depth Profiling of Frozen HEMA Hydrogels Diffusion Loaded with Keratinocyte Growth Factor-1 for controlled Release Applications</i>	Invited
16:40	Eller (student): <i>Real-time Localization of Single C<sub>60</sub> Impacts with Correlated Secondary Ion Detection</i>	Kato: <i>Simulation of Thermal Decomposition of leu-enkephalin Molecule by Quantum Molecular Dynamics Method for the Analysis of TOF-SIMS spectrum.</i>	Lee: <i>Organic Depth Profiling of a Nanostructured Delta Layer Reference Material using Large Argon Cluster Ions - A Preliminary Study</i>
17:00	Broderson: <i>Temperature Programmed ToF-SIMS Investigation of the NO<sub>2</sub>-Carbon Reaction</i>	Marchany: <i>Determination of Spatially Resolved Hydrolytic Degradation Kinetics of a Micropatterned Bioresorbable Polyester Membranes</i>	Moritani: <i>Site-specific Fragmentation of Polystyrene using Ar-gas Cluster TOF-SIMS</i>
17:20	Gonzalez: <i>The Combustion of Implanted Carbon in Polycrystalline Alumina Targets Followed by Secondary Ion Mass Spectrometry</i>	Gaspar: <i>Characterization of Organic Light Emitting Devices via Surface Analysis and Electron Microscopy</i>	Hiraoka: <i>Shallow Depth Profiling by Electrospray Droplet Impact</i>
17:40	Smentkowski: <i>Comparison of 3D Atom Probe and ToF-SIMS Data Collected on Nickel-based Superalloy Materials</i>	Fitzgerald (student): <i>Matrix Enhanced Secondary Ion Mass Spectrometry (ME SIMS) Using Ionic Liquid Matrices</i>	Fujiwara: <i>Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) using the Metal-Cluster-complex Primary Ion of Ir<sub>4</sub>(CO)<sub>7</sub><sup>+</sup></i>
18:00			
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18:40	Excursion /Reception at Hotel		
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Time	Session 1 Art conservation/Environm	Session 2: Nano/Semiconductor	Session WE 3: Cluster Ion Sources
Room	Wren (100)	Rossetti (100)	Churchill (350)
Session Chair	Amy Walker	Klaus Wittmaack	Ian Gilmore
8:20	Marie-Laure Abel: <i>Conservation of Plastics and Polymers: The Contribution of Surface Analysis</i>	Lee: <i>Direct Surface Analysis of Organic- and Bio-conjugated Nanoparticles</i>	Jones (student): <i>Comparison of MeV Monomer Ion and Cluster SIMS</i>
8:40	Invited	Rajagopalachary: <i>Examination of Individual Nanoparticles with Cluster SIMS</i>	Goacher (student): <i>Cluster Primary Ions vs. Monatomic Primary Ions: Differences in Secondary Cluster Ion Yields, Depth Resolutions, and Relative Sensitivity Factors for Inorganic Material Analysis</i>
9:00	McPhail: <i>Applications of SIMS and FIB SIMS in Conservation Science</i>	Chen (student): <i>Characterization and Quantification of Micropatterned Biointerface using Cluster-SIMS</i>	Tuccitto: <i>C60 Depth Profiling of Polymer-based Multilayers</i>
9:20	Tognazzi: <i>Characterization of Pigments and Binders in Painting Microsamples</i>	Reihs: <i>Control of Sub-Nanometer Surface Topography and Wetting in Binary Mixed Self-Assembled Monolayers</i>	Jiro Matsuo: <i>SIMS with Large Size Cluster Ions: Recent Advances and Challenges</i>
9:40	Konarski: <i>SIMS Depth Profile Analysis of Particles Collected in Urban Environment</i>	Pinnick (student): <i>Characterization of Individual Free-Standing Nano-Objects using Single Impact Cluster-SIMS</i>	Invited
10:00	Yatzor (student): <i>TOF-SIMS Imaging of Toxic Elements in Coal</i>	Azevedo: <i>Sol-gel Surface Treatment on Adobe Brick</i>	
10:20		International Committee Meetings/Announcements for Full Conference	
10:40		Voting for members in Churchill (350)	
11:00	Coffee	Coffee	Coffee
11:20	Buses to Excursion, Lunch on Bus		
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12:40	Excursion		
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17:00	Buses Return		
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19:00	Banquet		
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Time	Session TH: 1 Discussion Day on Depth Profiling Fundamentals and Organic Materials	Session Th 2: Industrial Applications of Frontier SIMS - Session sponsored by Ontario Centres of Excellence (OCE)
Room	Churchill (350)	Wren (100)
Session Chair	Greg Gillen	James Metson
8:40	Christine Mahoney: <i>Dynamic SIMS of Polymers</i>	Watts: <i>Chemical Characterization of the Fracture Surfaces of Polyester Resin and a Polyester Based Nanocomposite</i>
9:00	Invited	Kapadia: <i>Investigation of a Connector Electrical Failure</i>
9:20	Andrew Wee: <i>Ultra-shallow SIMS for Semiconductor Depth Profiling</i>	Faichuk: <i>ToF-SIMS Study of Surface Mechanical Attrition Treated Alloy 600 SG Tubing</i>
9:40	Invited	Guryanov: <i>SIMS Analysis of Rb-doped Hollow-core Photonic Band-gap Silica Fiber using CAMECA 4550 Instrument</i>
10:00	K. Wittmaack: <i>Fundamentals of Depth Profiling</i>	Sodhi: <i>Proposed ToF-SIMS/XPS Standardization of Characterization Method for Bonding Wires in Electronic Packaging Application</i>
10:20	Invited	Leonard: <i>ToF-SIMS Study of Tribochemical Properties of Sulfur-based Additives for the Lubrication of Steels in Boundary Lubrication Conditions</i>
10:40	Coffee	Coffee
11:00	Laurent Houssiau: <i>Molecular Depth Profiling with Reactive Ions, or why Chemistry Matters in Sputtering</i>	Poon: <i>Influence of Fluorine on Boron Diffusion in Germanium Preamorphized Silicon during Post-LTA Rapid Thermal Annealing</i>
11:20	Invited	Budri: <i>D&amp;TOF-SIMS Failure Analysis of P-Buried Layer from BiCMOS Transistors</i>
11:40	Panel Discussion/Discussion Questions	Juhel: <i>Trace Metal Contaminants Analysis on Silicon Surface by VPD-TOFSIMS and VPD-SIMS: Toward 1E6-1E7 at/cm<sup>2</sup></i>
12:00	Open for other participants to present	Ramamurthy: <i>The Effect of Grain Boundary Nickel Boride Precipitation on the Localized Corrosion of Alloy 400 Steam Generator Tubes at the Pickering Nuclear Generating Plant</i>
12:20	Discussion	Alexander Brennenstuhl: <i>The Application of SIMS for Studying Corrosion in the Nuclear Industry</i>
12:40		Invited
13:00	Lunch Break	Lunch Break

13:20	Lunch Break	Lunch Break
13:40	Lunch Break	Lunch Break
Session Chair	Christine Mahoney	Michaeleen Pacholski, Rohm and Haas
14:00	Ngo (student): <i>Analysis of Organic Multilayered Samples for Optoelectronic Devices by (low-energy) Dynamic SIMS</i>	Anna Belu: <i>Applications of TOF-SIMS in the Medical Device Industry</i>
14:20	Py (student): <i>Investigation of Fullerene Depth Distribution in Polymer-Fullerene Blends using ToF-SIMS</i>	Invited
14:40	Morris: <i>The Influence of Beam Energy on Apparent Layer Thickness and Interface Shape using Ultra Low Energy O<sub>2</sub><sup>+</sup> SIMS on Surface Si<sub>1</sub>-xGe<sub>x</sub></i>	Nicholas: <i>Surface Chemical Imaging of Lactose: Coated and Not</i>
15:00	Fletcher: <i>Investigating the Effects of Temperature and Hydration State on Bio-materials for Depth Profiling Analysis</i>	Brunon: <i>ToF-SIMS Characterizations of Antimicrobial Textiles</i>
15:20	Niehus: <i>MCs<sub>x</sub><sup>+</sup> Depth Profiling Using Cluster Primary Ions</i>	Sodhi: <i>ToF-SIMS Studies on Chlorhexidine and its Reaction Products with Sodium Hypochlorite to Ascertain Decomposition Products</i>
15:40	Coffee	Coffee
16:00	Dr. Temel Büyüklımanlı: <i>Solutions to Ultra Shallow Boron Distribution Analysis Challenges</i>	Industrial Panel Discussion Rana Sodhi, Panel Leader
16:20	Invited	
16:40	Simons: <i>Semiconductor Applications of a Large Geometry SIMS Instrument</i>	Careers With SIMS  A special panel for students and postdocs  Session sponsored by NSERC
17:00	Van Hove: <i>Zero-energy SIMS: Towards Quantitative Depth Profiling with High Spatial and High Depth Resolution</i>	
17:20	Bryan: <i>Optimization of C<sub>60</sub> Sputtering Conditions for Depth Profiling of Organics</i>	
17:40	Konarski: <i>Effects of Vacuum Heating in AISI 410 and AISI 321 Stainless Steels' Surface Layer Revealed by SIMS/GDMS Depth Profile Analysis</i>	
18:00	Poster Session	Poster Session
18:20		
18:40		
19:00		

Time	Session Fri 1: Organic Materials	Session Fri 2: Semiconductor/Dynamic	Session Fri 3: Depth Profiling
Room	Churchill (350)	Rossetti (100)	Wren (100)
Session Chair	John Watts	Gary Mount	David McPhail
8:40	Amy Walker: <i>Construction of Complex Two- and Three-Dimensional Nanostructures: Towards Molecular Electronics</i>	Wu: <i>Quantitative Investigation of BCN Films by Dynamic SIMS using the MCs<sub>x</sub><sup>+</sup> Mode</i>	Vandervorst: <i>Quantitative Depth Profiling of SiGe-Multilayers with the Atomprobe</i>
9:00	Invited	Herrmann: <i>Optimization and Comparing of Depth Profiling in GaAs and GaSb with TOF-SIMS</i>	Mine: <i>Molecular Sputtering Yields of Polystyrene, PMMA and Polycarbonate Sputtered with Low Energy Reactive Ions</i>
9:20	Wahoud (student): <i>Origin of the Oscillatory Phase during Cs<sup>+</sup> Sputtering of Organic Materials</i>	Masudome: <i>Chemical States Depth Profiling of Thin Metal Oxide Layer by TOF-SIMS using Bi<sub>3</sub><sup>+</sup> + Cluster</i>	Wehbe: <i>Depth Profiling of Amino-acid and Vitamin Layers using Low Energy Cs<sup>+</sup> and O<sub>2</sub><sup>+</sup> Projectiles</i>
9:40	Hagenhoff: <i>Daily ToF-SIMS Instrument Control Using Polycarbonate Material</i>	Brewer: <i>Liquid Cluster Secondary Ion Mass Spectrometry: Signal Enhancement through Glycerol Drop Addition</i>	Mouhib: <i>C60 Molecular Depth Profiling of Bilayered Polymer Films using ToF-SIMS</i>
10:00	Shimizu (student): <i>The Characterization of the Interfacial Interaction between Methylene Diphenyl Diisocyanate and Metal Substrates using ToF-SIMS</i>	Tomita: <i>Evaluation of Atomic Mixing for Silicon Atoms in Silicon Isotope Superlattices under Cesium and Oxygen Ion Bombardments</i>	Ninomaya: <i>Molecular Depth Profiling of Polymers with Large Ar Cluster Ion Beams</i>
10:20	Crewdson: <i>Characterizing the Physical Effects of Hyperthermal Hydrogen Bombardment of Polymer Surfaces</i>	Zhu: <i>Accurate SIMS Characterization of SiGe with Low Energy Ion Beams</i>	Hida: <i>Suppressing the Re-distribution of Boron in Crystalline Silicon during SIMS Analysis</i>
10:40	Coffee	Coffee	Coffee
11:00	De Mondt: <i>Ultra-low-angle Microtomy to Back up S-SIMS Molecular Depth Profiling with C<sub>60</sub><sup>+</sup> and Bi<sub>n</sub><sup>+</sup> for the Nanoscale Analysis of High-tech Industrial Materials</i>	Zhu: <i>Using C<sub>60</sub><sup>+</sup> Sputtering to Improve Detection Limit of Nitrogen in Zinc Oxide</i>	Rading: <i>Dual Beam Depth Profiling of Organic Materials: Variations of Analysis and Sputter Beam Conditions</i>
11:20	Marino: <i>The Adsorption of an Acrylated Resin on Hot-Dip Galvanized Steel: A ToF-SIMS Study</i>	Portier: <i>Study of the Metal-Oxide Interface of Irradiated Zr-based Alloys</i>	Merkulov: <i>Quantitative Analysis of SiON Layers using ULE Cs<sup>+</sup> and Negative Secondary Ions</i>
11:40	Nie: <i>ToF-SIMS of OPA Self-Assembled Monolayers on Silicon Oxide and Aluminum Oxide Surfaces</i>	Brennenstuhl: <i>The Application of SIMS Dynamic SIMS to Characterize the Localized Corrosion of Alloy 800 Nuclear Steam Generator Tubes</i>	Giubertoni: <i>Ultra Low Energy Boron Ion Implants in Silicon Analyzed by Not-oxydizing O<sub>2</sub><sup>+</sup> Bombardment and Synchrotron Radiation Grazing Incidence X-ray Fluorescence</i>
12:00	Conference Closes		
12:20			